



STB20N65M5, STI20N65M5, STP20N65M5, STW20N65M5

N-channel 650 V, 0.160 Ω typ., 18 A MDmesh™ V Power MOSFET
in D²PAK, I²PAK, TO-220 and TO-247 packages

Datasheet — production data

Features

Order codes	V _{DS} @ T _{Jmax}	R _{DS(on)} max	I _D
STB20N65M5	710 V	0.19 Ω	18 A
STI20N65M5			
STP20N65M5			
STW20N65M5			

- Worldwide best R_{DS(on)} * area
- Higher V_{DSS} rating and high dv/dt capability
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

These devices are N-channel MDmesh™ V Power MOSFETs based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

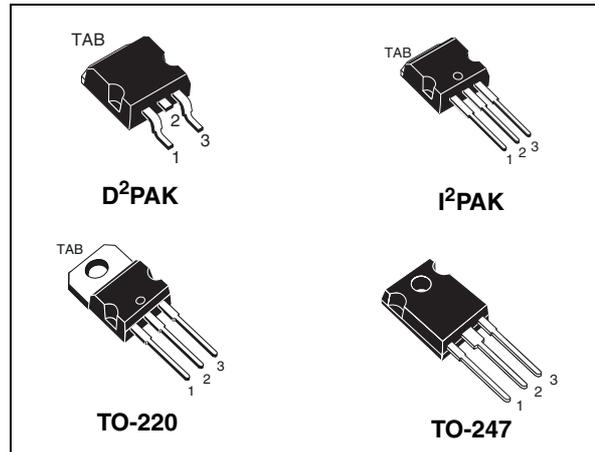


Figure 1. Internal schematic diagram

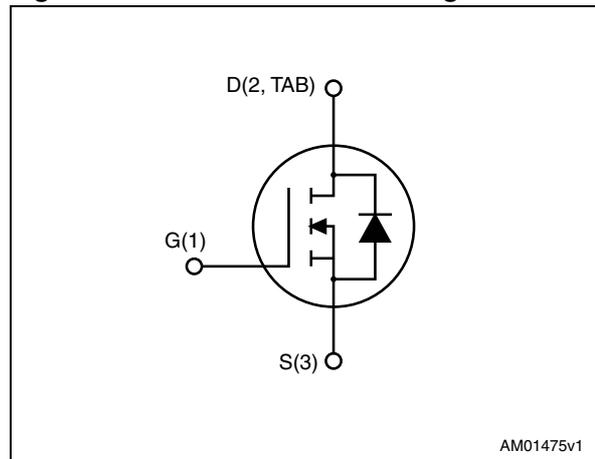


Table 1. Device summary

Order codes	Marking	Package	Packaging
STB20N65M5	20N65M5	D ² PAK	Tape and reel
STI20N65M5		I ² PAK	Tube
STP20N65M5		TO-220	
STW20N65M5		TO-247	

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	18	A
I_D	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	11.3	A
$I_{DM}^{(1)}$	Drain current (pulsed)	72	A
P_{TOT}	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	130	W
$dv/dt^{(1)}$	Peak diode recovery voltage slope	15	V/ns
T_{stg}	Storage temperature	- 55 to 150	$^\circ\text{C}$
T_j	Max. operating junction temperature	150	$^\circ\text{C}$

1. $I_{SD} \leq 18\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$; $V_{DS\text{ peak}} < V_{(BR)DSS}$, $V_{DD}=400\text{ V}$

Table 3. Thermal data

Symbol	Parameter	Value			Unit
		D ² PAK	I ² PAK, TO-220	TO-247	
$R_{thj-case}$	Thermal resistance junction-case max	0.96			$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max		62.5	50	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	30			$^\circ\text{C}/\text{W}$

1. When mounted on 1 inch² FR-4, 1 Oz copper board.

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	4	A
E_{AS}	Single pulse avalanche energy (starting $t_j=25\text{ }^\circ\text{C}$, $I_d=I_{AR}$; $V_{dd}=50\text{ V}$)	270	mJ

2 Electrical characteristics

($T_C = 25\text{ °C}$ unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1\text{ mA}$, $V_{GS} = 0$	650			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = 650\text{ V}$ $V_{DS} = 650\text{ V}$, $T_C = 125\text{ °C}$			1 100	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 25\text{ V}$			± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 9\text{ A}$		0.160	0.19	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0$	-	1434	-	pF
C_{oss}	Output capacitance			38		pF
C_{rss}	Reverse transfer capacitance			3.7		pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0\text{ to }520\text{ V}$, $V_{GS} = 0$	-	118	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related			35		pF
R_G	Intrinsic gate resistance	$f = 1\text{ MHz}$ open drain	-	3.5	-	Ω
Q_g	Total gate charge	$V_{DD} = 520\text{ V}$, $I_D = 9\text{ A}$, $V_{GS} = 10\text{ V}$	-	36	-	nC
Q_{gs}	Gate-source charge			7.5		nC
Q_{gd}	Gate-drain charge			18		nC

1. Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(v)}$	Voltage delay time	$V_{DD} = 400 \text{ V}$, $I_D = 12 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$	-	43	-	ns
$t_{r(v)}$	Voltage rise time			7.5		ns
$t_{f(i)}$	Current fall time			7.5		ns
$t_{c(off)}$	Crossing time			11.5		ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		18	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				72	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 18 \text{ A}$, $V_{GS} = 0$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 18 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ (see)	-	288		ns
Q_{rr}	Reverse recovery charge			4		μC
I_{RRM}	Reverse recovery current			27		A
t_{rr}	Reverse recovery time	$I_{SD} = 18 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$	-	342		ns
Q_{rr}	Reverse recovery charge			4.7		μC
I_{RRM}	Reverse recovery current			28		A

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for D²PAK, I²PAK, TO-220

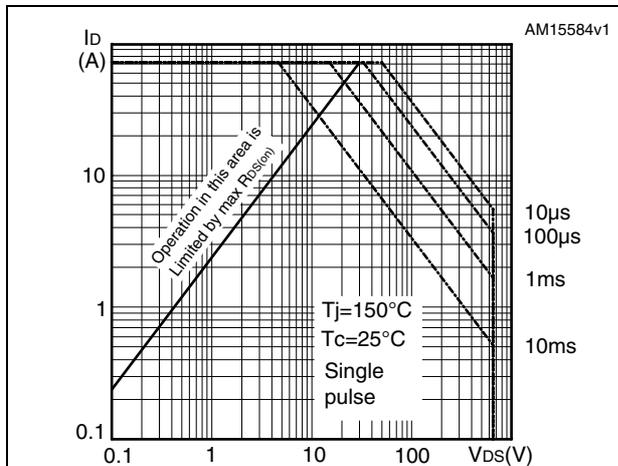


Figure 3. Thermal impedance for D²PAK, I²PAK, TO-220

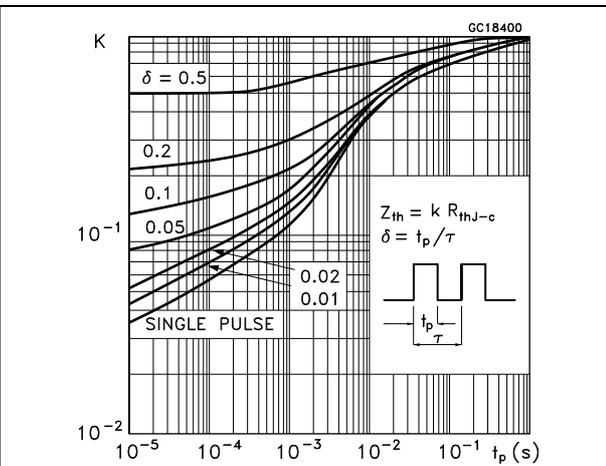


Figure 4. Safe operating area for TO-247

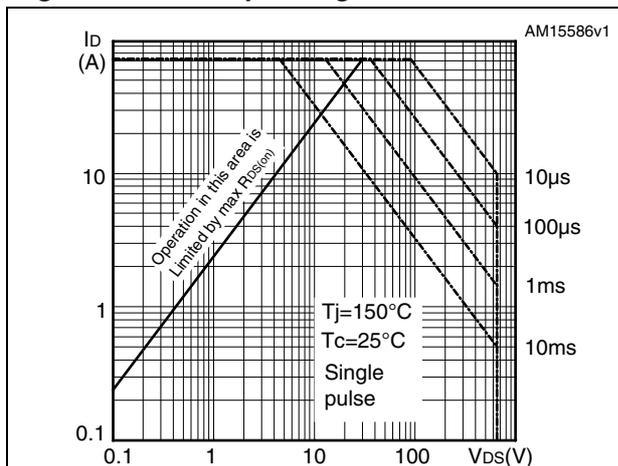


Figure 5. Thermal impedance for TO-247

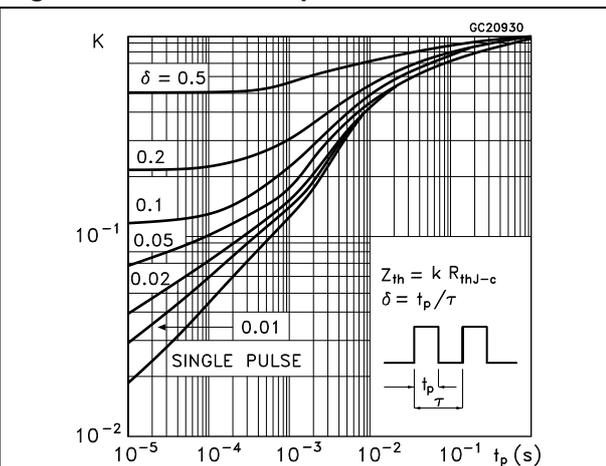


Figure 6. Output characteristics

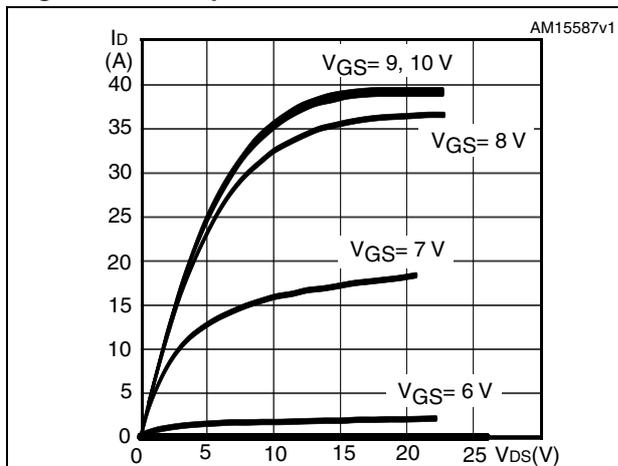


Figure 7. Transfer characteristics

